IN THE ABSTRACT

Please replace the Abstract with the following rewritten paragraph:

~~Abstract~~

~~Arrangement of contact areas and test areas on patterned semiconductor chips~~**SEMICONDUCTOR WAFER WITH ELECTRICALLY CONNECTED CONTACT AND TEST AREAS**

Abstract

The invention relates to an arrangement of contact areas ~~(1)~~ and test areas ~~(2)~~ on patterned semiconductor chips ~~(3)~~. The contact areas ~~(1)~~ and the test areas ~~(2)~~ are electrically connected to one another via a conduction web ~~(4)~~. Whereas the contact areas ~~(1)~~ are arranged in a first region ~~(5)~~, which has no components of an integrated circuit, the test areas ~~(2)~~ lie in a second region ~~(7)~~ of the top side of the semiconductor chip ~~(3)~~, which region has components ~~(6)~~ of an integrated circuit.

~~[figure 1]~~